

Search Notes

Application/Control No.

10/722,807

Examiner

David Faber

Applicant(s)/Patent under
Reexamination

LEHIKONEN ET AL.

Art Unit

2178

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|------------|-----------|----------|
| 715 | 501.1, 513 | 2/24/2006 | DF |
| 709 | 245, 246 | 2/24/2006 | DF |
| 707 | 10 | 2/24/2006 | DF |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|-----------|------|
| EAST (Search Notes Attached) | 2/24/2006 | DF |
| PLUS (Search Notes Attached) | 2/24/2006 | DF |
| Consulted with Primary Examiner William Bashore | 2/24/2006 | DF |
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